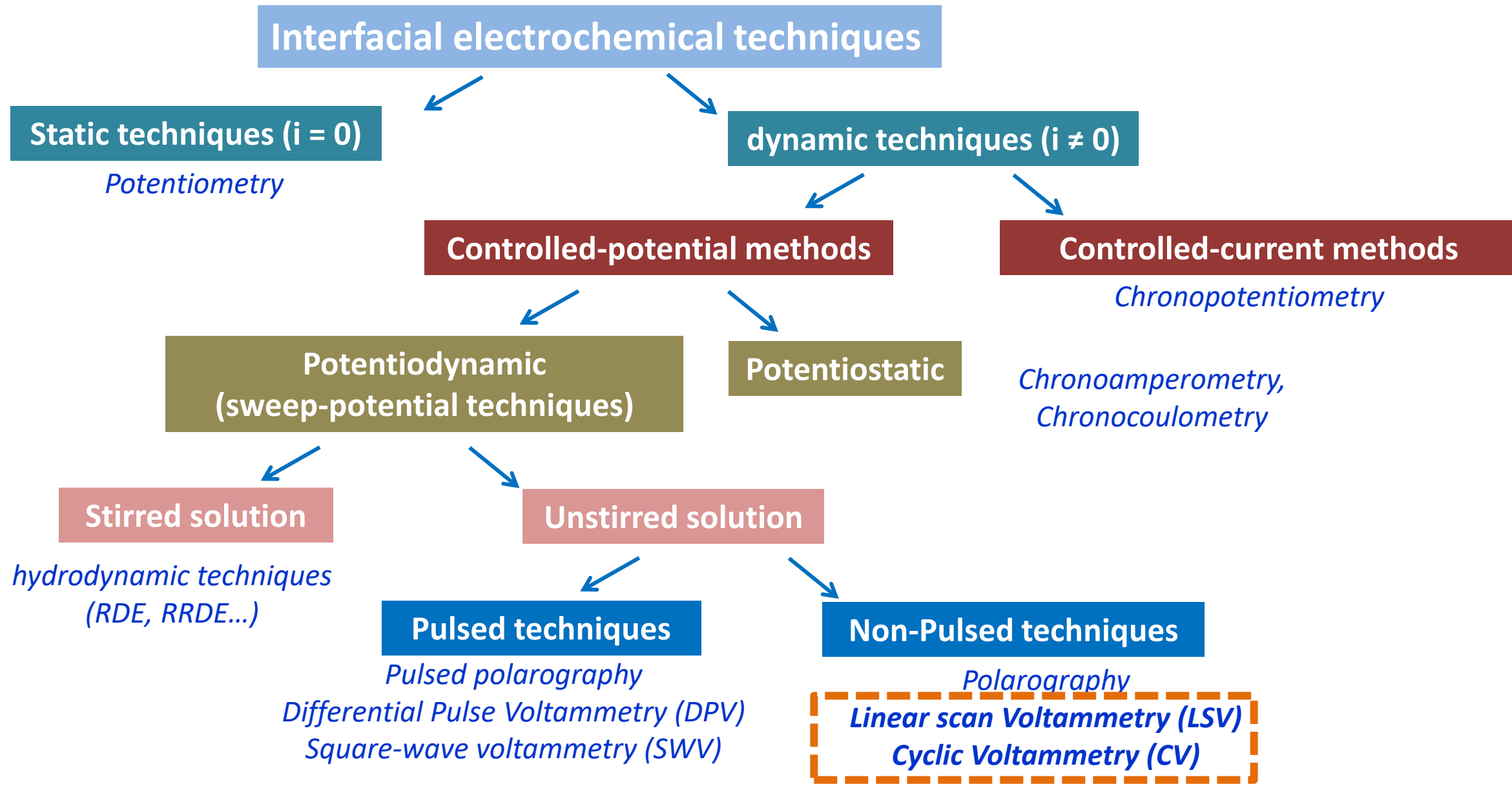


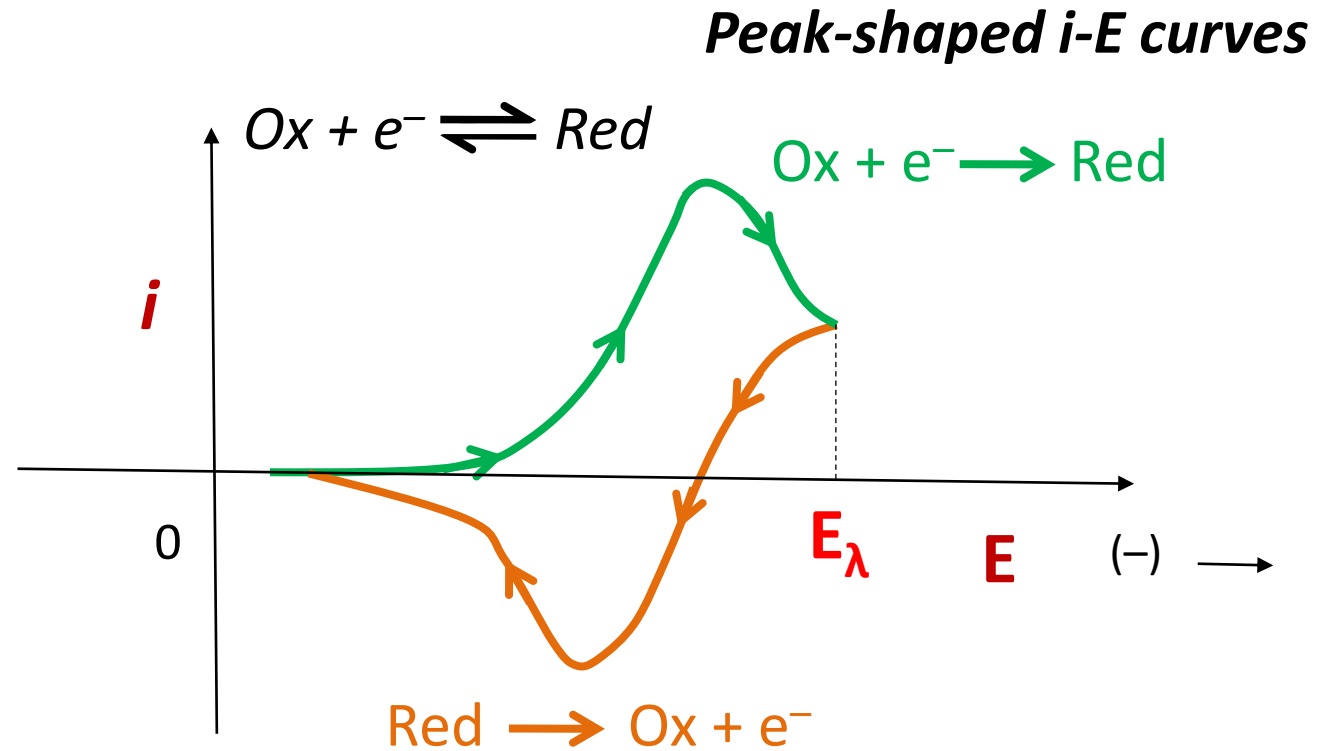
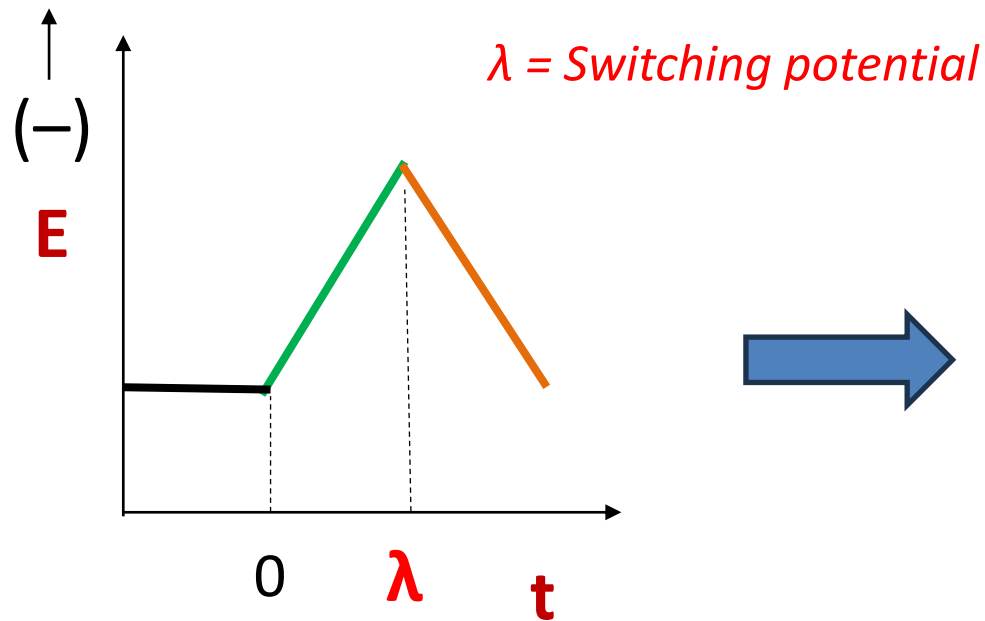
Basic classification of electrochemical methods



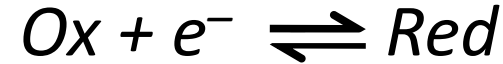
Potential sweep electrochemical methods: voltammetry

$$\left\{ \begin{array}{ll} (0 < t \leq \lambda) & E(t) = E_i - vt \quad \text{Linear Scan Voltammetry (LSV)} \\ (t > \lambda) & E(t) = E_i - 2v\lambda + vt \quad \text{Cyclic Voltammetry (CV)} \end{array} \right. \quad v = \frac{dE(t)}{dt}$$

Scan rate (V/s)



Linear Scan Voltammetry: boundary conditions



- Planar electrode
- **Initial conditions (1)** $C_{Ox}(x, 0) = C_{Ox}^*$ $C_{Red}(x, 0) = 0$ for $t = 0$
- **Semi-infinite conditions (2)** (linear diffusion) $\lim_{x \rightarrow \infty} C_{Ox}(x, t) = C_{Ox}^*$
- **Flux balance (3)**
$$J_{Ox}(0, t) = -J_{Red}(0, t)$$
$$D_{Ox} \left(\frac{\partial C_{Ox}(x, t)}{\partial x} \right)_{x=0} + D_{Red} \left(\frac{\partial C_{Red}(x, t)}{\partial x} \right)_{x=0} = 0$$

Common boundary conditions to potential step techniques

Linear Scan Voltammetry: boundary conditions

- Linear potential scan with time (LSV) (4)

$$E(t) = E_i - \boldsymbol{v}t \quad \text{for } 0 < t \leq \lambda$$

Surface concentration condition

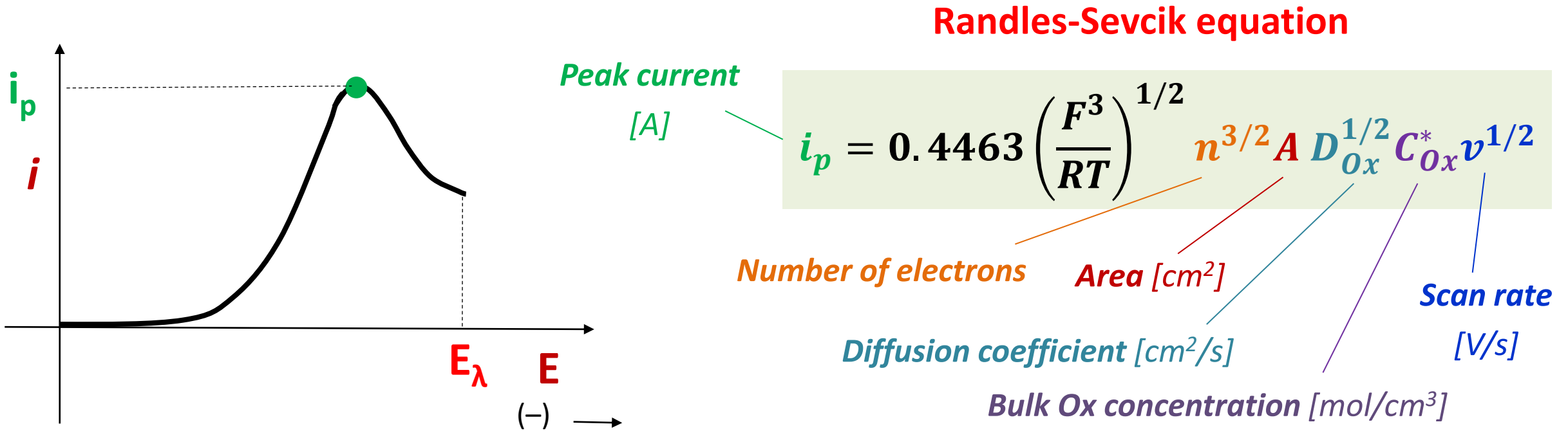
$$\frac{C_{Ox}(0, t)}{C_{Red}(0, t)} = \exp \left[\frac{nF}{RT} (E - E^{0'}) \right] \quad \text{Nernstian redox system (reversible)}$$

$$\boxed{\frac{C_{Ox}(0, t)}{C_{Red}(0, t)} = f(t) = \exp \left[\frac{nF}{RT} (E_i - \boldsymbol{v}t - E^{0'}) \right]}$$

Time-dependent Nernst-type equation

(more complicated rigorous mathematical treatment for solving the equations)

Linear Scan Voltammetry for a nernstian system

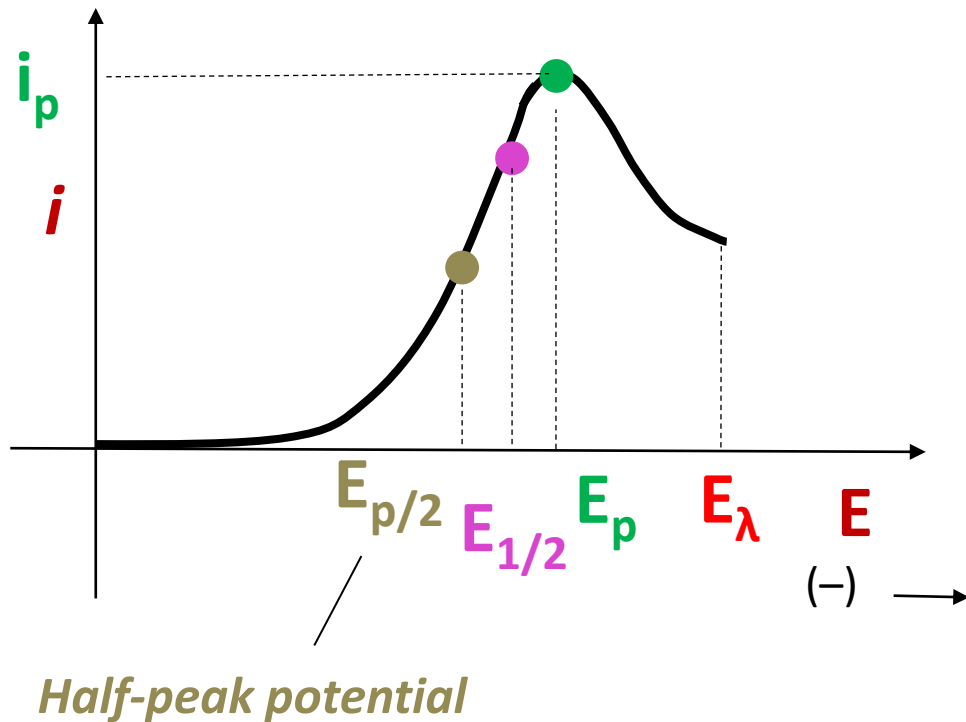


At $T = 25^\circ\text{C}$

$$i_p = (2.69 \times 10^5) n^{3/2} A D_{Ox}^{1/2} C_{Ox}^* v^{1/2}$$

- $i_p \propto v^{1/2}$: for a reversible wave, it indicates a **diffusion control** (Cottrellian $i_d \propto t^{-1/2}$)
- D_{Ox} can be estimated from $i_p / v^{1/2} C_{Ox}^*$ (if A and n are known)
- n can be estimated from $i_p / v^{1/2} C_{Ox}^*$ (if A and D_{Ox} are known)

Linear Scan Voltammetry for a nernstian system



$$E_p - E_{1/2} = -1.109 \frac{RT}{nF} = -28.5 \text{ mV} \quad (25^\circ\text{C}, n=1)$$

Peak potential
(independent on v!!!)

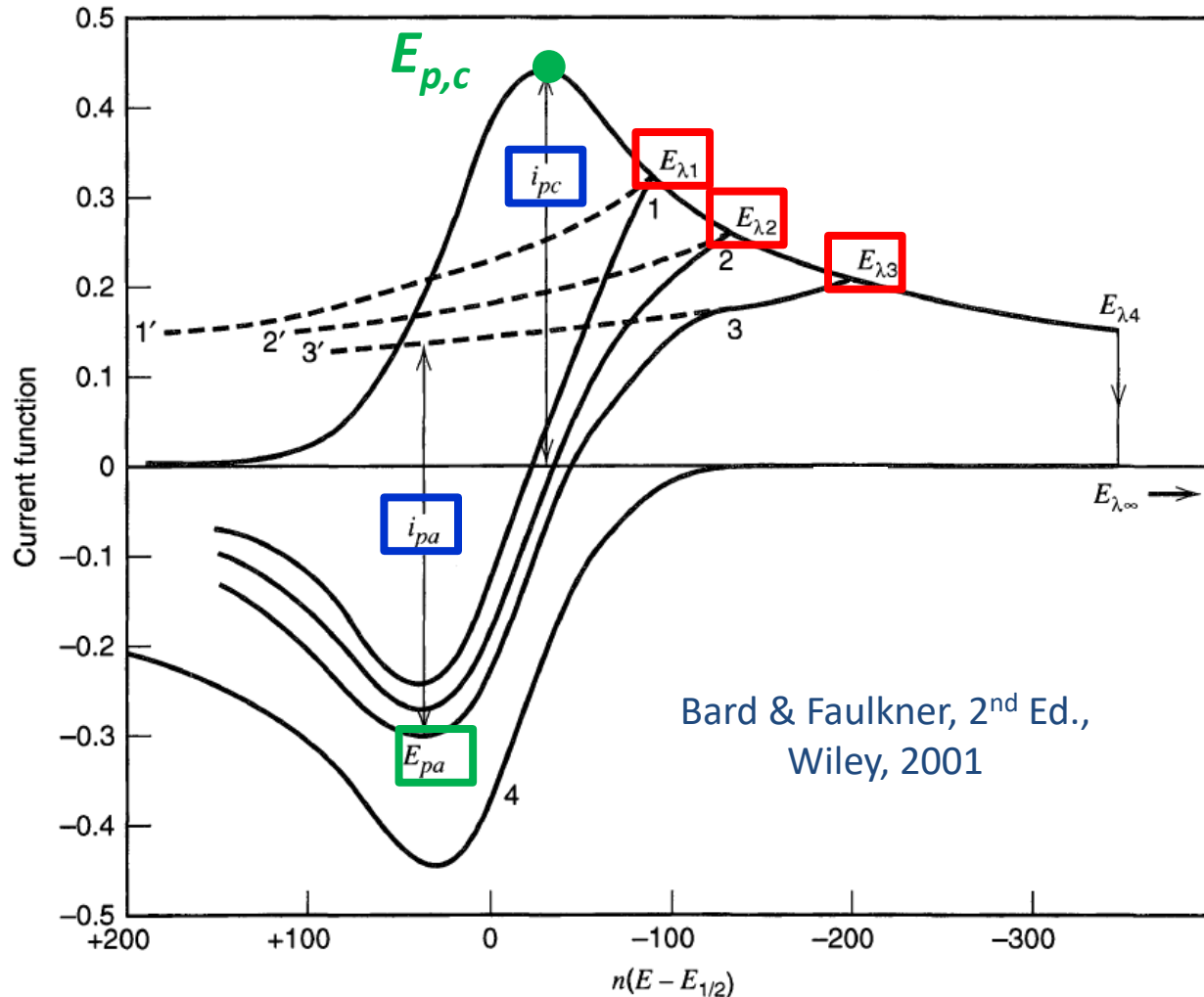
$\approx$ midway between E_p and $E_{p/2}$

$$|E_p - E_{p/2}| = 2.20 \frac{RT}{nF} = 56.5 \text{ mV} \quad (25^\circ\text{C}, n=1)$$

Peak width (independent on v)

Cyclic Voltammetry (CV): a reversible nernstian system

i-E cyclic voltammograms (CVs)



Cyclic Voltammetry (CV) (Reversal technique)

$$(0 < t \leq \lambda) \quad E(t) = E_i - vt$$

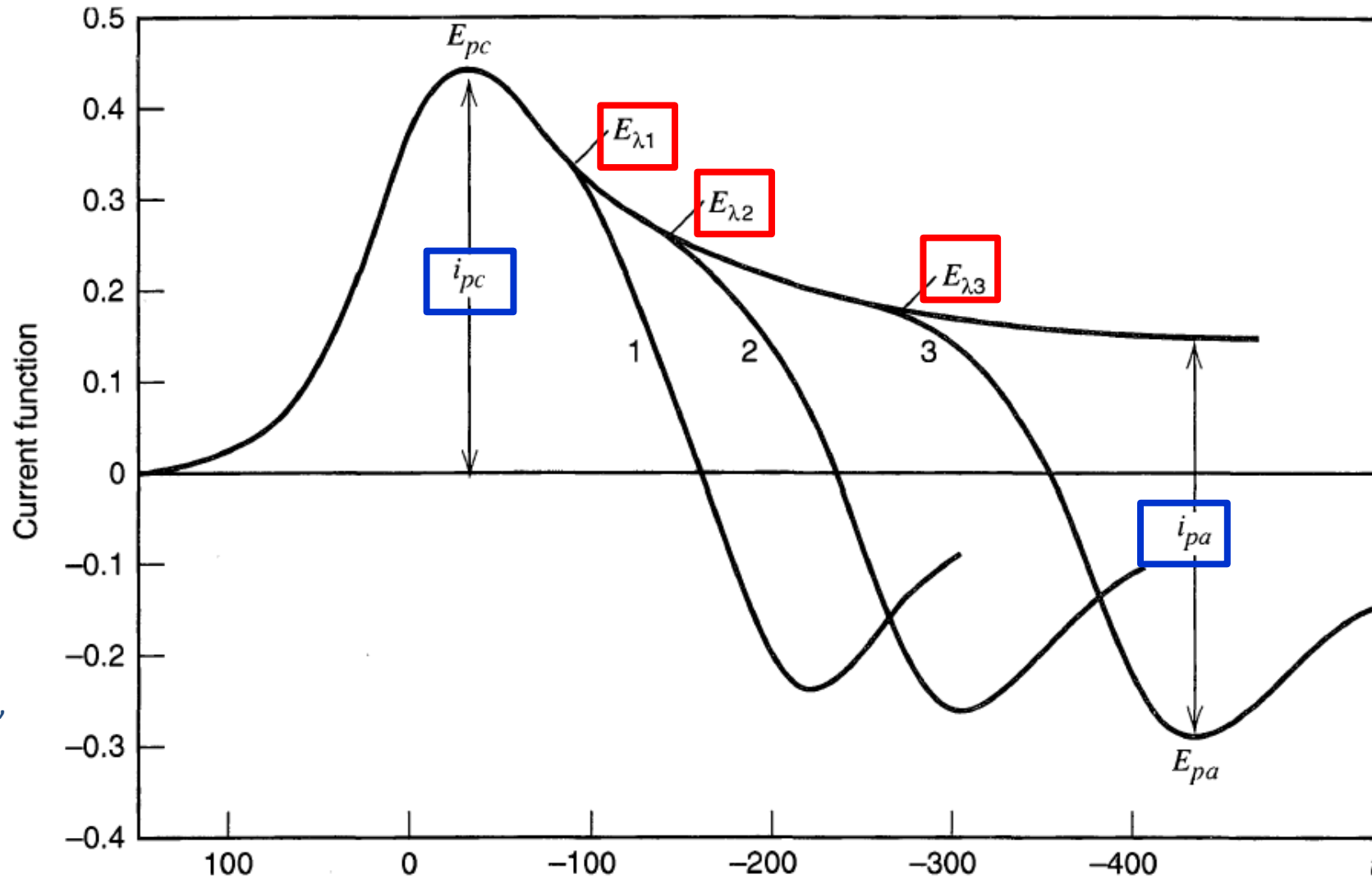
$$(t > \lambda) \quad E(t) = E_i - 2v\lambda + vt$$

- Shape of CVs depends on E_λ
- For $E_\lambda - E_{p,c} > (35/n) \text{ mV}$, the reverse peak has the same shape as the forward one
- For a reversible wave, $i_{p,a}/i_{p,c} = 1$ (independent on v)
- $i_{p,a}$ is measured from the decaying cathodic current as baseline
- ΔE_p only slightly depends on E_λ

$$\Delta E_p = E_{p,a} - E_{p,c} = 2.3 \frac{RT}{nF} \sim 57 \text{ mV} \quad (25^\circ\text{C}, n=1)$$

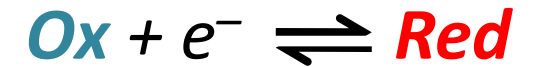
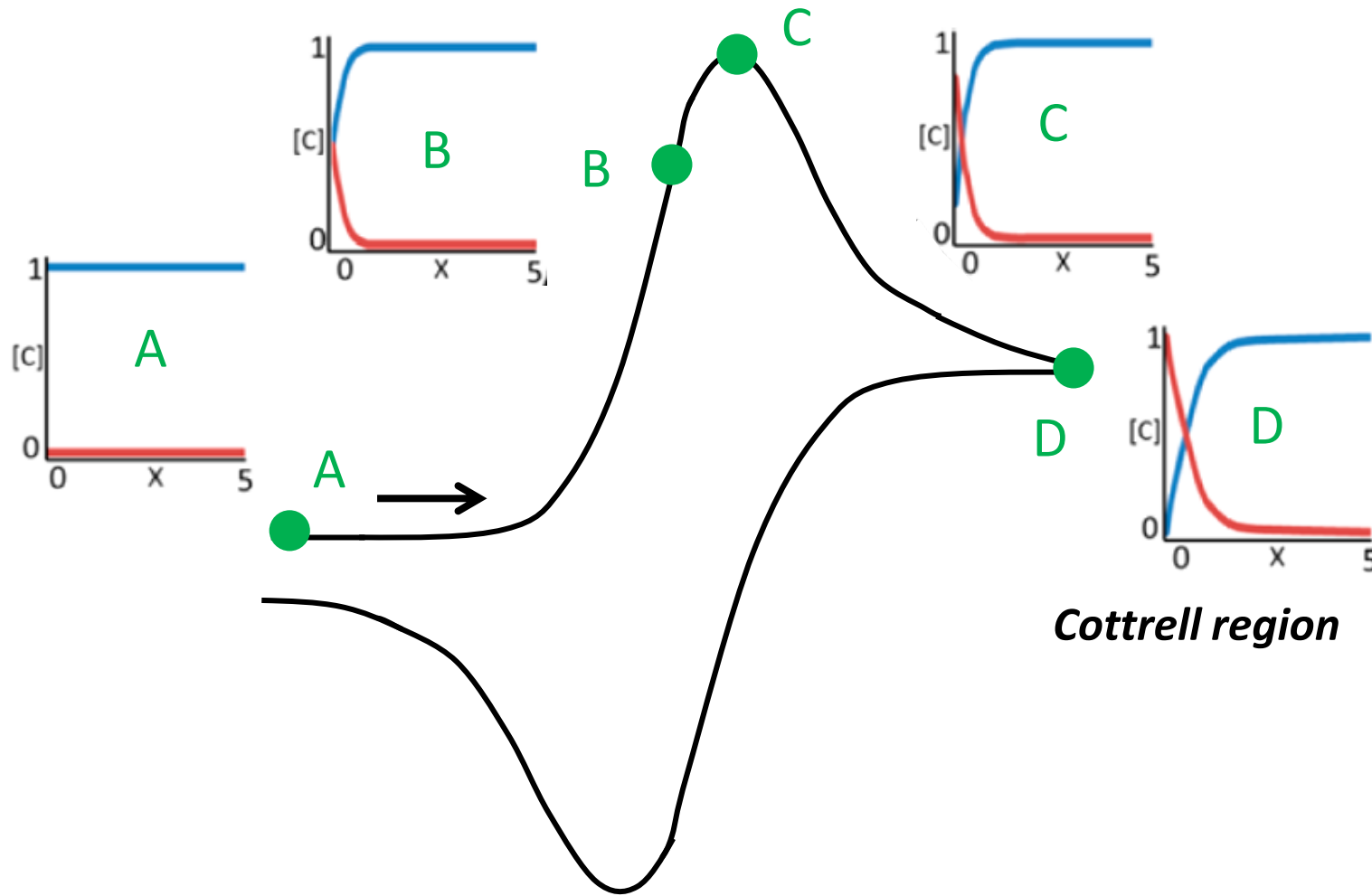
Cyclic Voltammetry (CV): a reversible nernstian system

i-t curves



Bard & Faulkner, 2nd Ed.,
Wiley, 2001

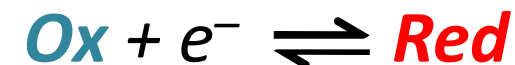
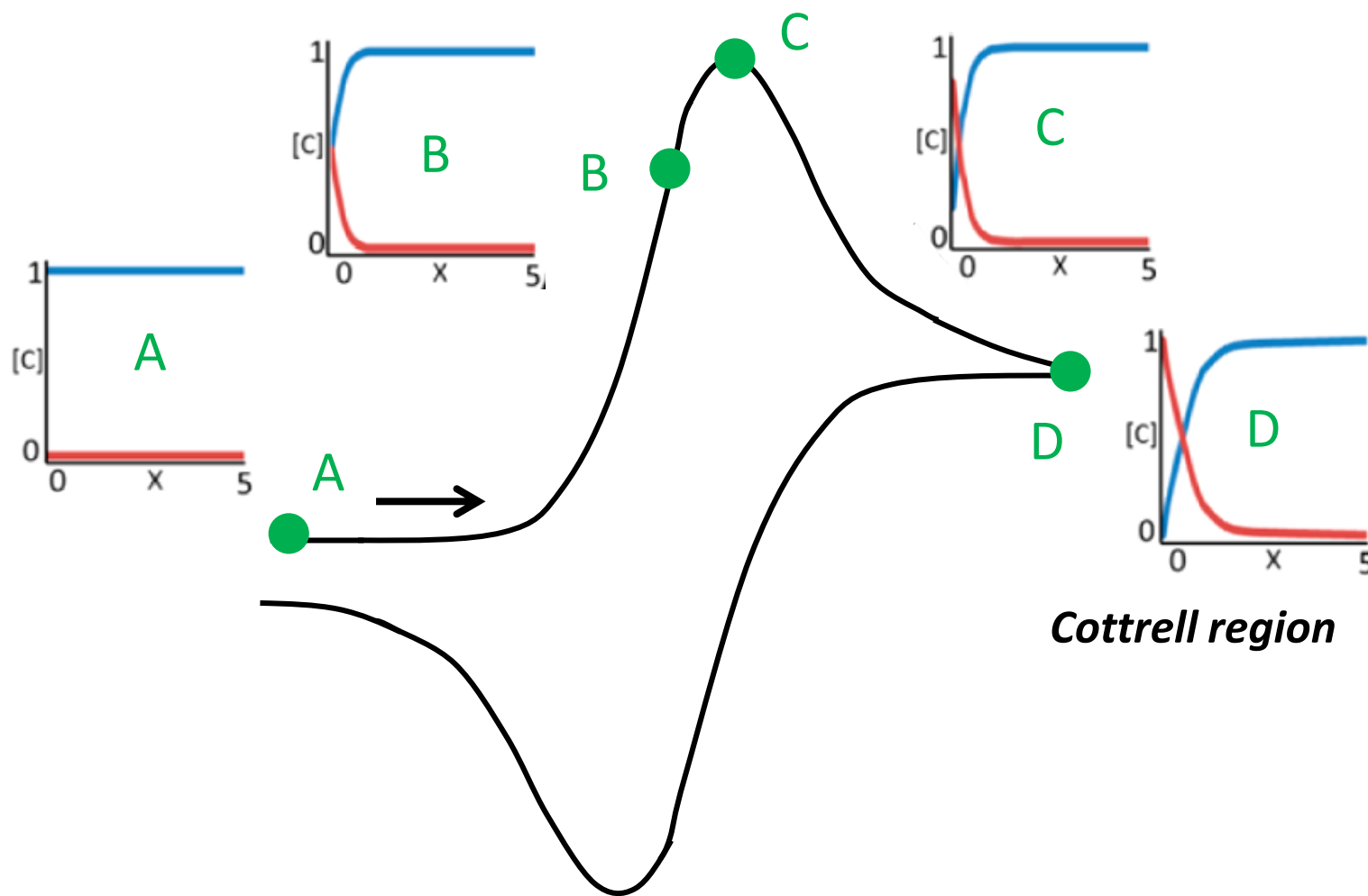
Understanding the peak shape: the concentration profiles



$$\frac{C_{\text{Ox}}(0, t)}{C_{\text{Red}}(0, t)} = \exp \left[\frac{nF}{RT} (E - E^{0'}) \right]$$

- Concentration of the electroactive species (Ox/Red) near the electrode change over time according to the **Nernst equation**
- **A → D: cathodic scan**, Ox is **depleted** at the surface
- **C**: maximum cathodic current ($i_{p,c}$), dictated by mass transport of Ox from bulk to surface

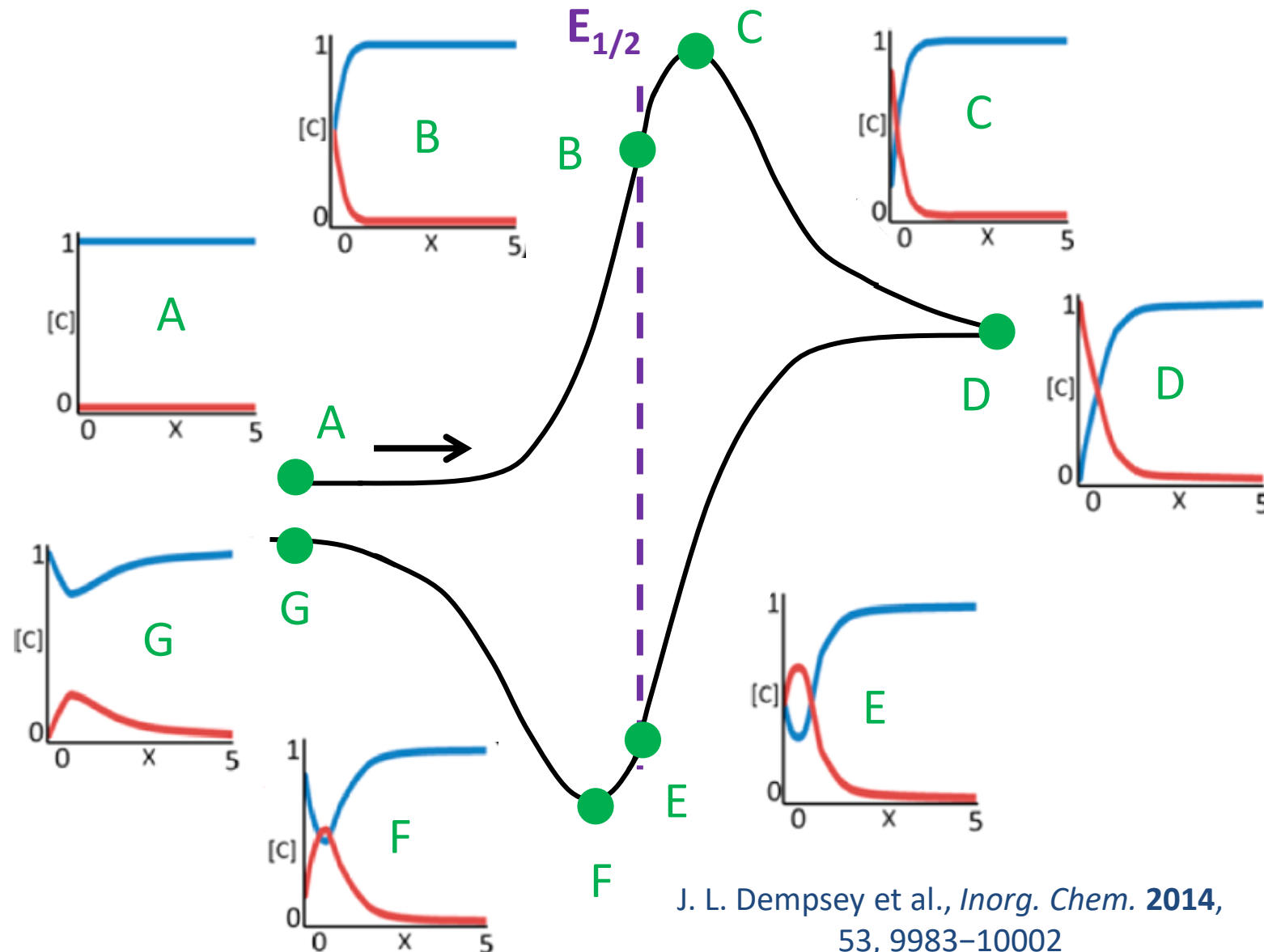
Understanding the peak shape: the concentration profiles



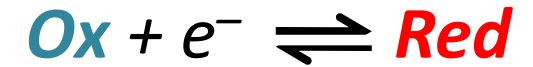
$$\frac{C_{\text{Ox}}(0, t)}{C_{\text{Red}}(0, t)} = \exp \left[\frac{nF}{RT} (E - E^{0'}) \right]$$

- **Thickness of the diffusion layer (δ) grows during the scan** ($\partial C / \partial x$ diminishes) $\rightarrow$ slower mass transport from bulk to surface $\rightarrow i$ decrease
- δ depends on the CV timescale
- **δ decreases with increasing scan rates** ($\delta \sim \sqrt{Dt}$, $t \propto 1/v$)

Understanding the peak shape: the concentration profiles



J. L. Dempsey et al., *Inorg. Chem.* **2014**,
53, 9983–10002



$$\frac{C_{\text{Ox}}(0, t)}{C_{\text{Red}}(0, t)} = \exp \left[\frac{nF}{RT} (E - E^{0'}) \right]$$

- **D → G: reverse anodic scan** (Red is oxidized to Ox as E becomes increasingly positive)
- **B and E:**

$$C_{\text{Ox}}(0, t) = C_{\text{Red}}(0, t)$$

$$E \approx E_{1/2}$$

$$E^{0'} \approx \frac{1}{2} (E_{p,c}(\text{C}) + E_{p,a}(\text{F}))$$

- ΔE_p is due to the **diffusive mass transport** of the electroactive species from/to surface-bulk

Reversible voltammetric waves: diagnostic criteria

Potential

- $E_{p,c}$ independent on the scan rate (ν)
- $\Delta E_p = 57/n \text{ mV}$ (at 25°C) independently on the scan rate (this value varies with T!!!)
- Assuming that $D_{\text{Ox}} = D_{\text{Red}}$, the **formal potential** $E^{0'}$ can be measured as:

$$E^{0'} = \frac{1}{2} (E_{p,c} + E_{p,a})$$

Current

- $i_{p,c} / \nu^{1/2}$ constant with the scan rate (ν) (freely diffusing redox species)
- $i_{p,a} / i_{p,c}$ constant and equal to 1 (independent on the scan rate)

The effect of double layer capacitance

- In potential sweep experiments, capacitive current (i_c) always flows and is **directly proportional to the scan rate** (v):
- Both the faradaic and the capacitive currents increase with the scan rate, but i_c **increases faster**

$$i_c \propto v$$

$$i_p \propto v^{1/2} \quad \text{Randles-Sevcik equation}$$

$$\frac{|i_c|}{i_p} = \frac{(10^{-5}) C_d v^{1/2}}{2.69 n^{3/2} D_{Ox}^{1/2} C_{Ox}^*}$$

- The **extraction of the faradaic component in CV at high scan rates is problematic**, especially in the presence of **low concentration** of the electroactive species (baseline correction)

The effect of double layer capacitance

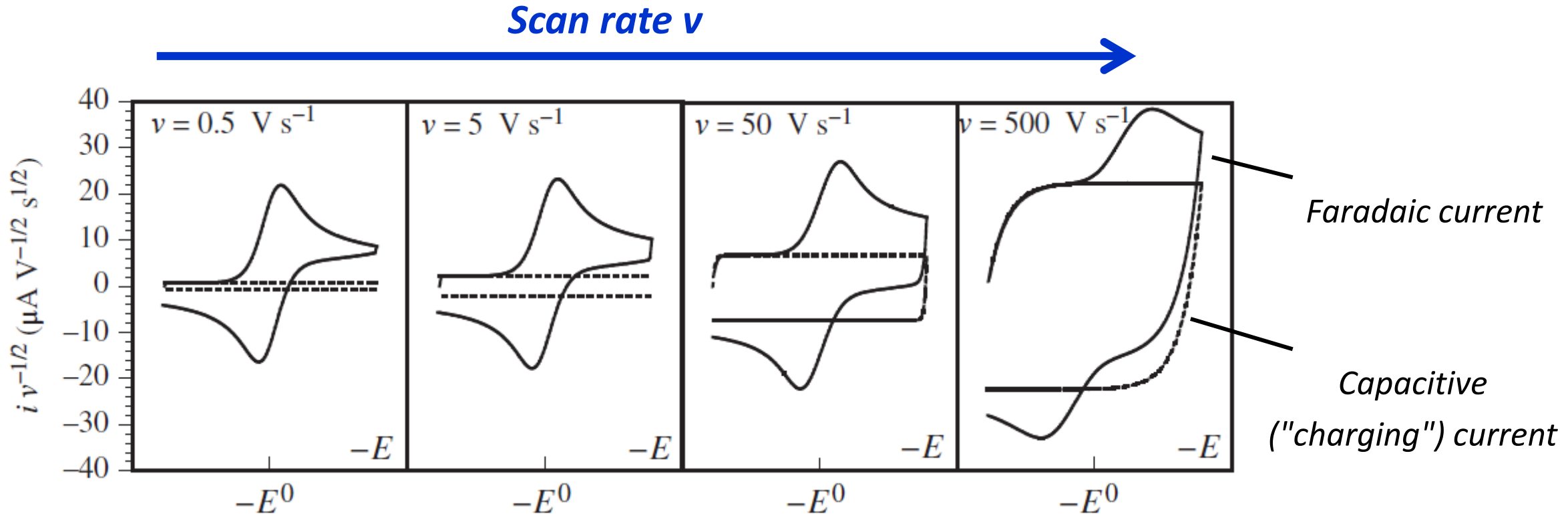
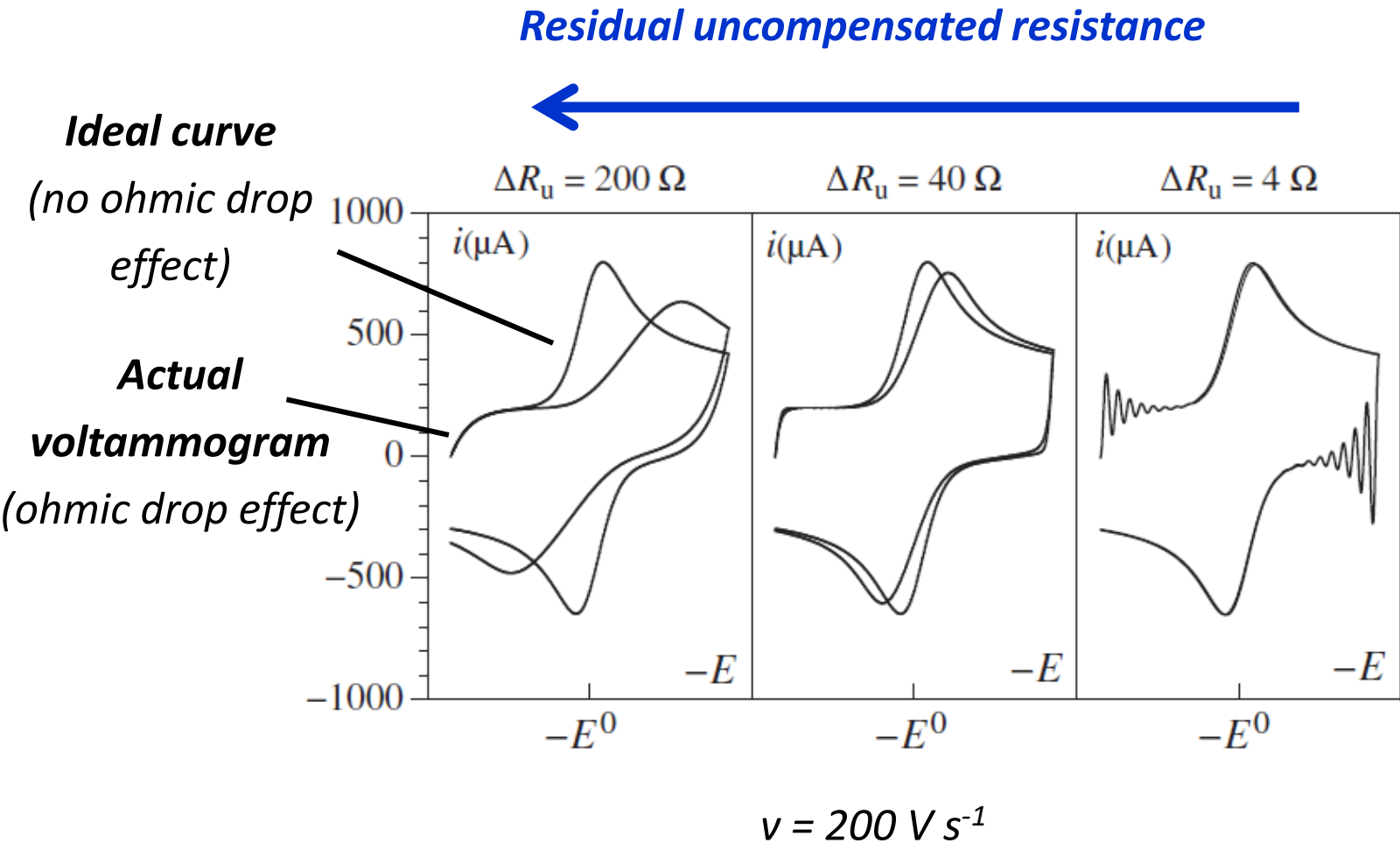


Figure 1.7 Faradaic and double-layer charging currents for a cyclic voltammetric Nernstian wave. —, total current; · · ·, capacitive component. $S = 0.05 \text{ cm}^2$, $C^0 = 5 \times 10^{-4} \text{ M}$, $C_d = 1 \mu\text{F}$, $R_u = 100 \Omega$.

The effect of the ohmic drop



- Uncompensated resistance (iR_u) may lead to **severe distortion** of the CV shape, typically shifting away the cathodic and anodic peaks from each other (ΔE_p increase, lower i_p , peak broadening)
- The effect of the ohmic drop increases at **high scan rates** (higher current), **causing E_p to be a function of v** (diagnostic criteria for uncompensated ohmic drop)